



# Multi-Scale Modeling of Photovoltaic Module Electrically Conductive Adhesive Interconnects for Reliability Testing

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<sup>1</sup>*National Renewable Energy Laboratory, Golden, USA*

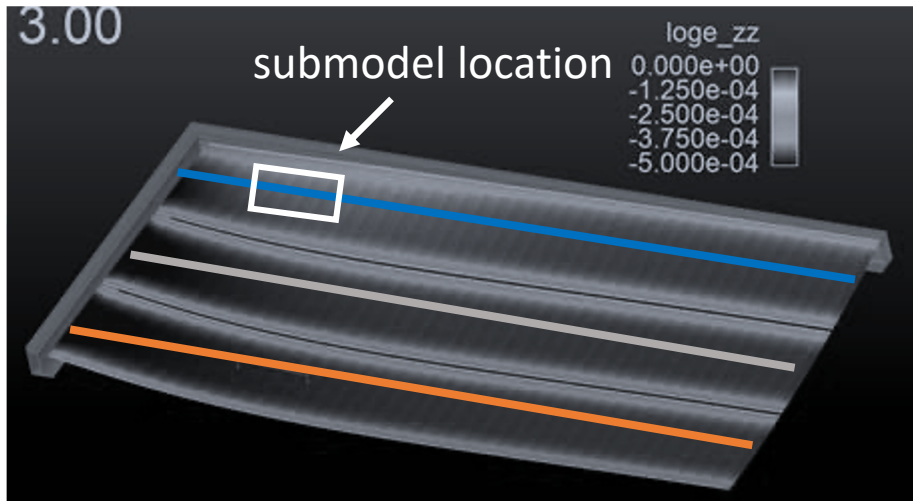
<sup>2</sup>*Sandia National Laboratories, Albuquerque, USA*

# goal and approach

Elucidate the driving force for ECA *degradation* in shingled PV modules and how it is developed.

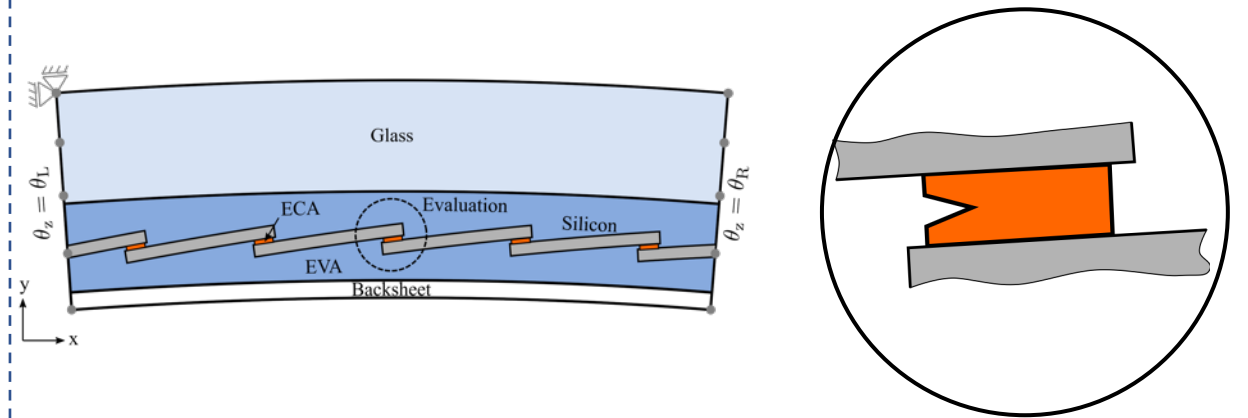
Employ a 3D model of a complete shingled cell module to inform a more detailed submodel.  
This multi-scale approach allows accurate simulations of small-scale phenomenon.

full 3D module model



input: module loading conditions  
output: module-level deflection

2D module model

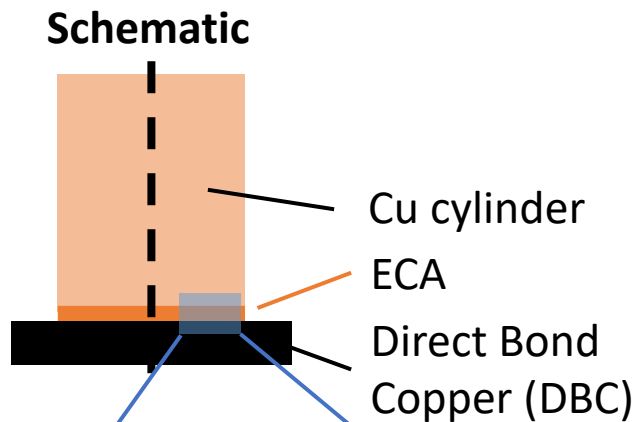
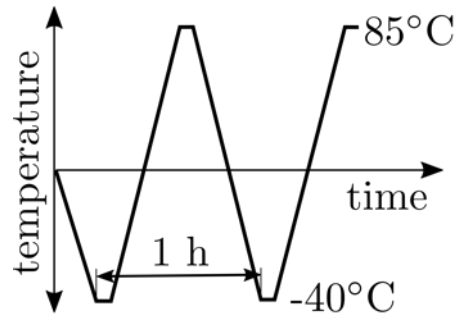


input: module-level deflection  
output: interconnect-level response

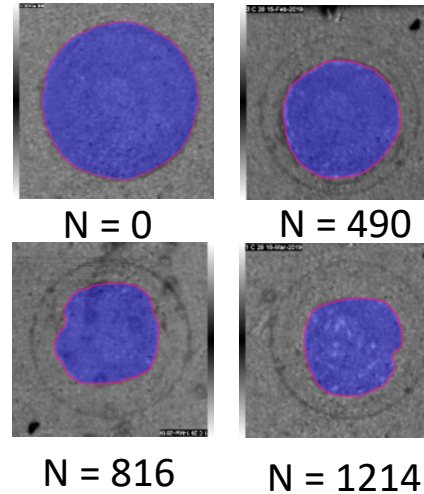
# motivation

Cracking and debonding of an ECA marketed for PV interconnection found through accelerated thermal cycling

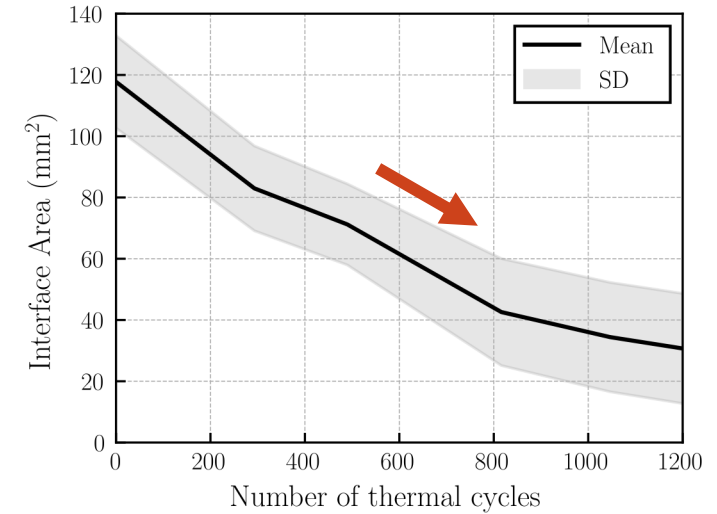
## Thermal Cycling Test Vehicle



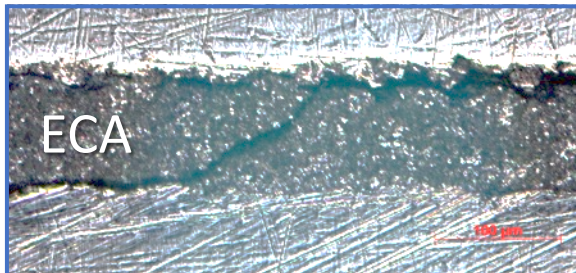
## interface area



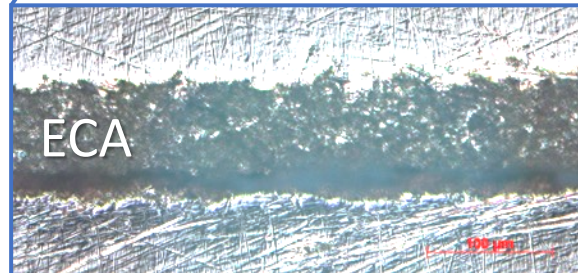
## mechanical degradation



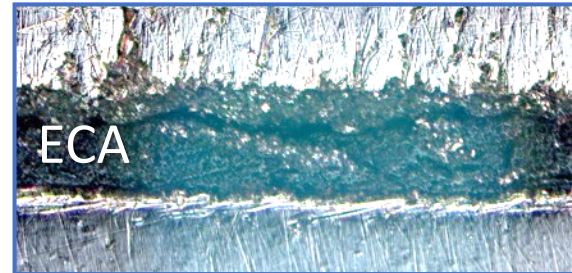
## Mixed failure mode



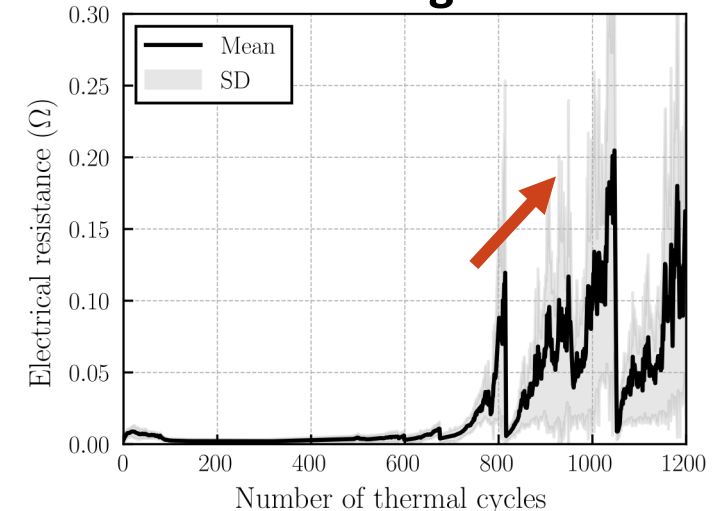
## Adhesive failure mode



## Cohesive failure mode



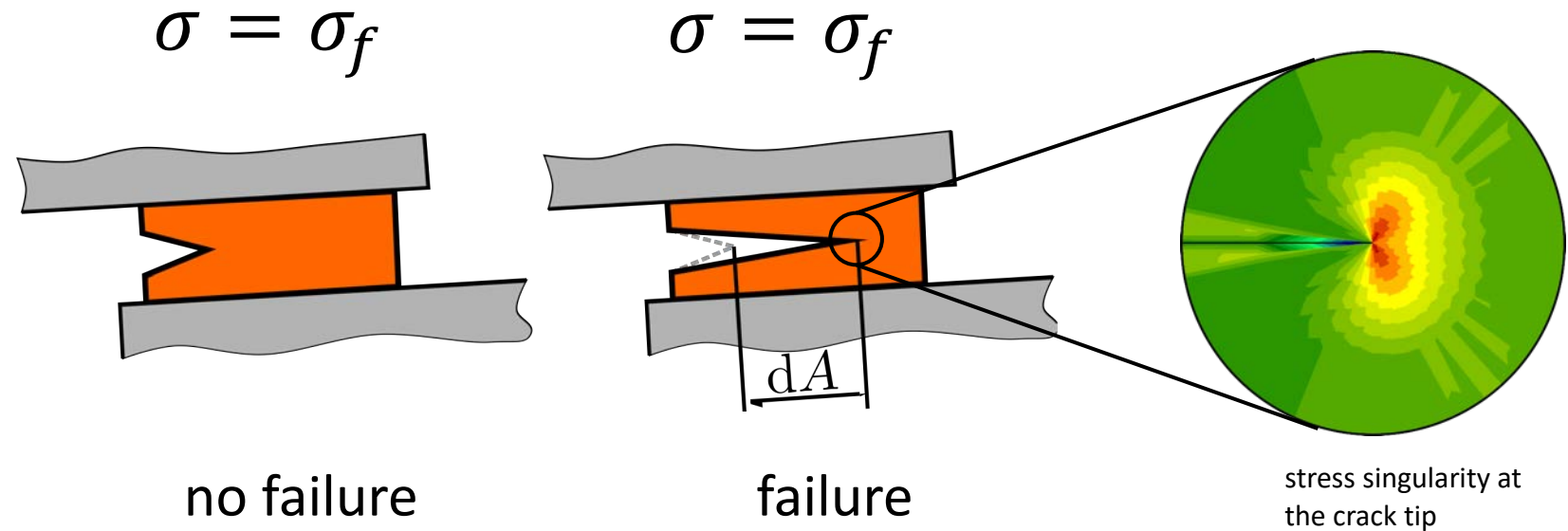
## electrical degradation



# approach

Evaluation of the strain energy release rate,  $G$

A **maximum stress theory** for interconnect failure is too general to inform degradation behavior

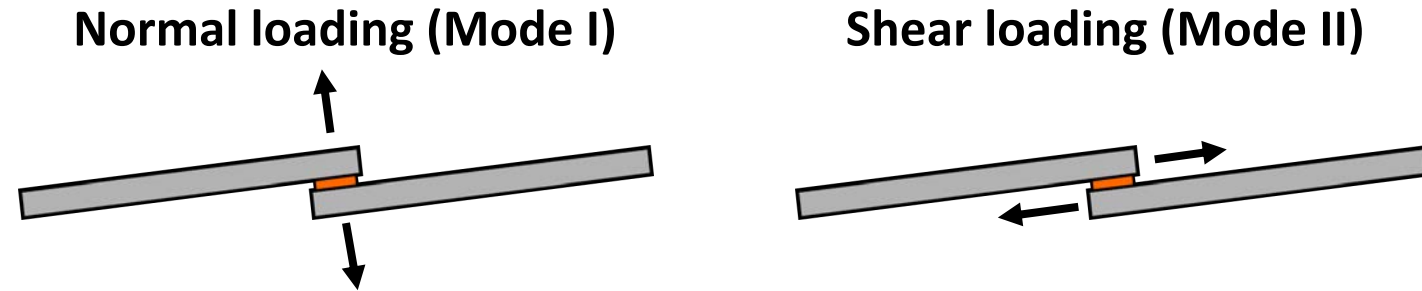


The **strain energy release rate**,  $G$ , accounts for both loading and crack specific geometry

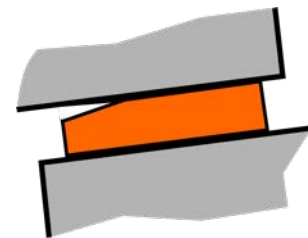
Provides a specific metric (driving force) capable of predicting degradation behavior

# approach

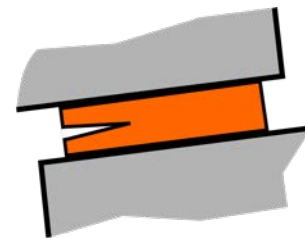
We evaluate the **driving force,  $G$** , for two modes of crack opening:



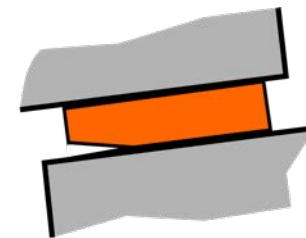
and six different crack locations within the interconnect



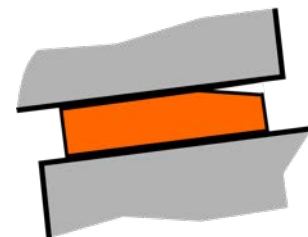
(a) top left



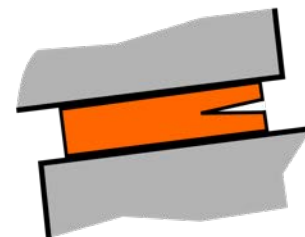
(b) middle left



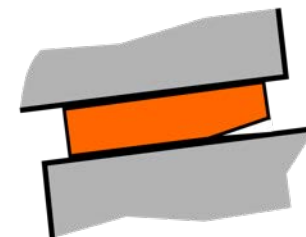
(c) bottom left



(d) top right



(e) middle right

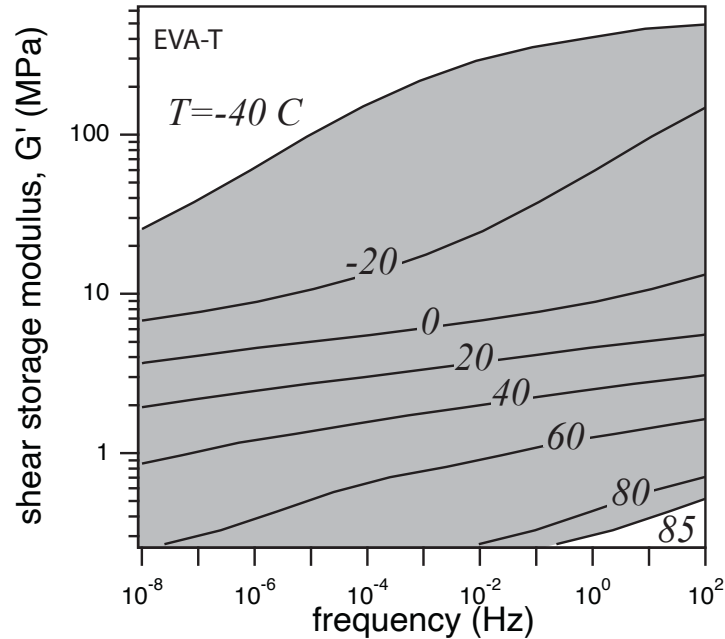


(f) bottom right

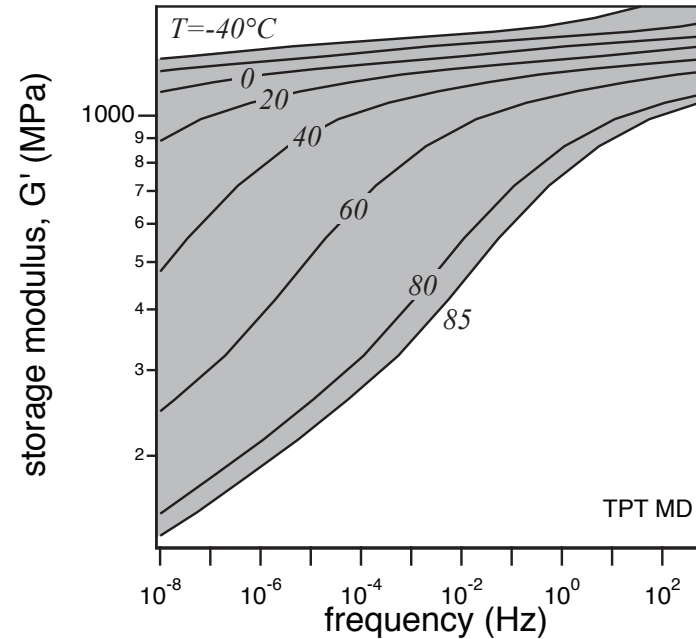
# approach

## Material models

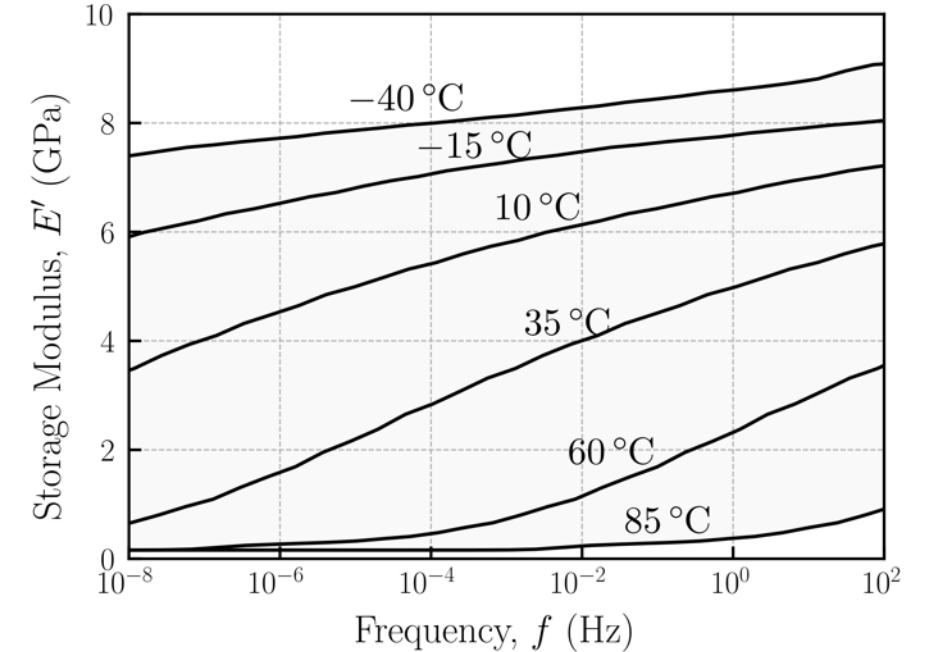
### EVA encapsulant



### TPT backsheet



### ECA



M. Springer and N. Bosco, "Linear viscoelastic characterization of electrically conductive adhesives used as interconnect in photovoltaic modules," *Progress in Photovoltaics: Research and Applications*, vol. n/a, no. n/a, doi: 10.1002/pip.3257.

N. Bosco, M. Springer and X. He, "Viscoelastic Material Characterization and Modeling of Photovoltaic Module Packaging Materials for Direct Finite-Element Method Input", accepted by *Journal of Photovoltaics*, June 2020.

# preliminary simulations

minimum energy approach - arbitrary stress-free temperature

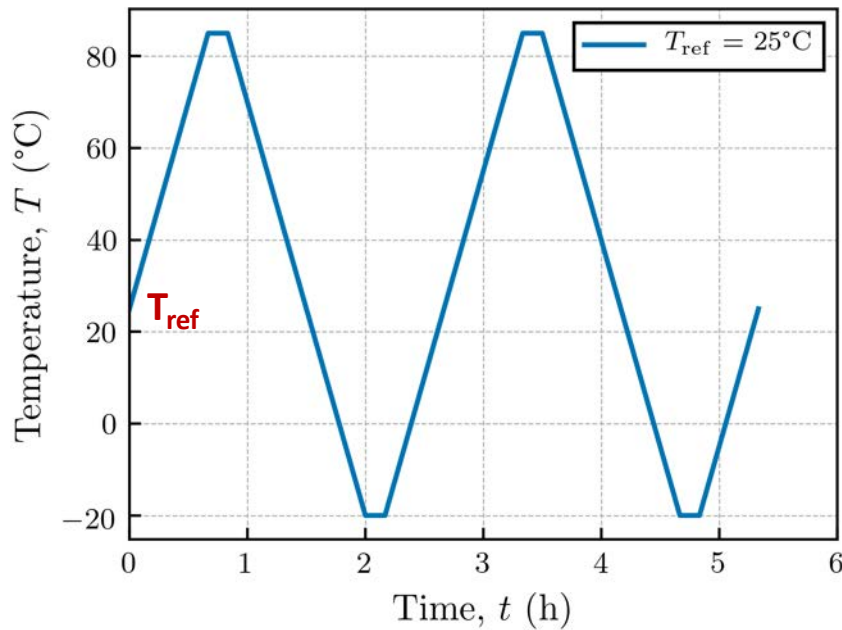
**Example stress-free temperature: 25°C**

**Loading conditions: 2 thermal cycles (T<sub>ref</sub> -> 85°C -> -20°C -> T<sub>ref</sub>) x 2**

**Total strain energy = Elastic strain energy + Viscoelastic dissipation energy**

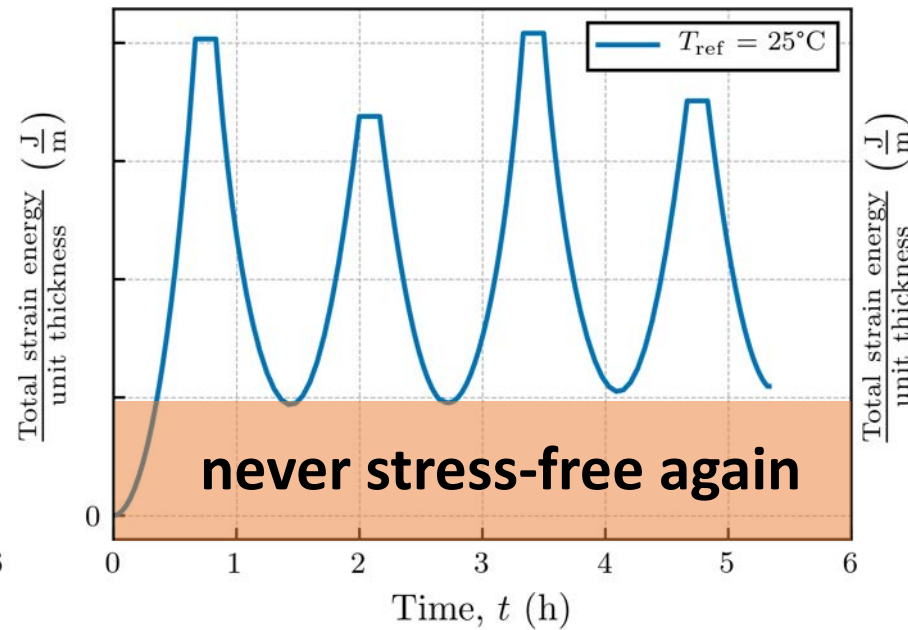
## thermal cycling

*over time*

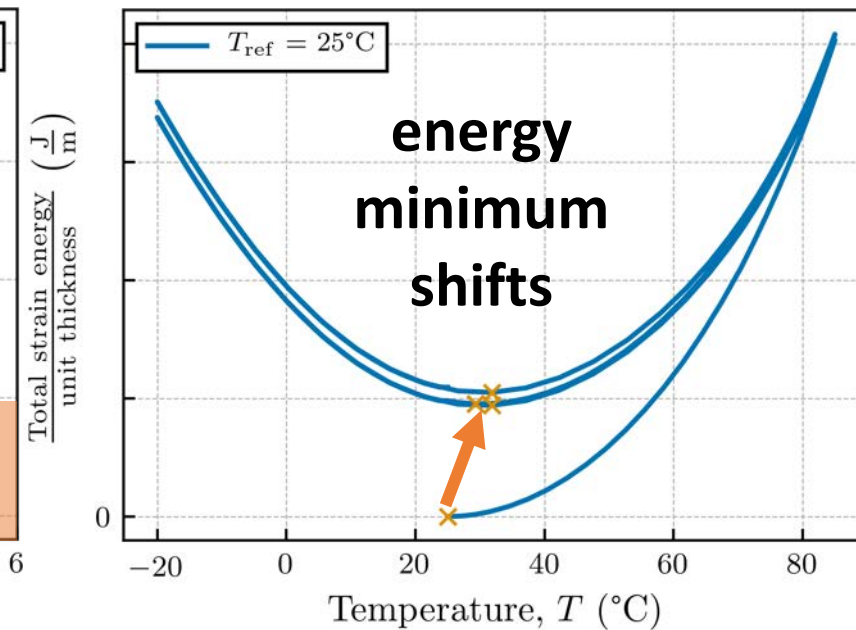


## total strain energy

*over time*



*over temperature*



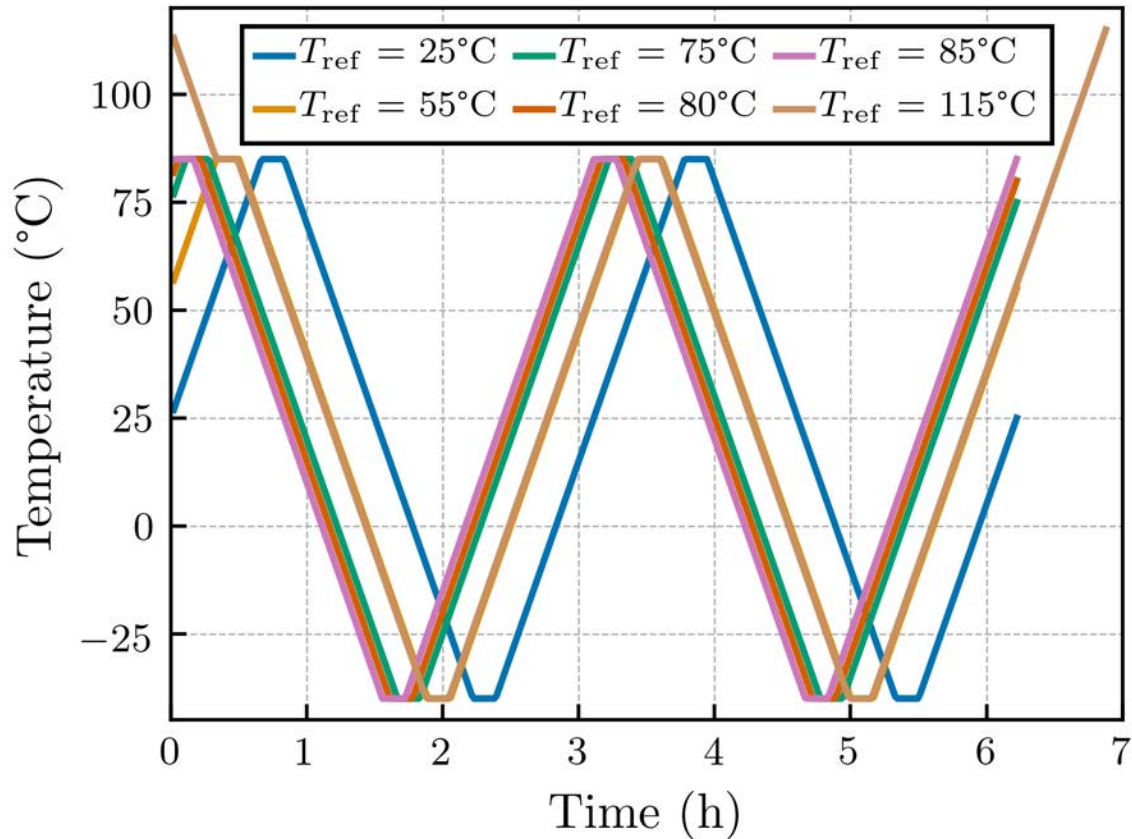
# preliminary simulations

minimum energy approach - arbitrary stress-free temperature

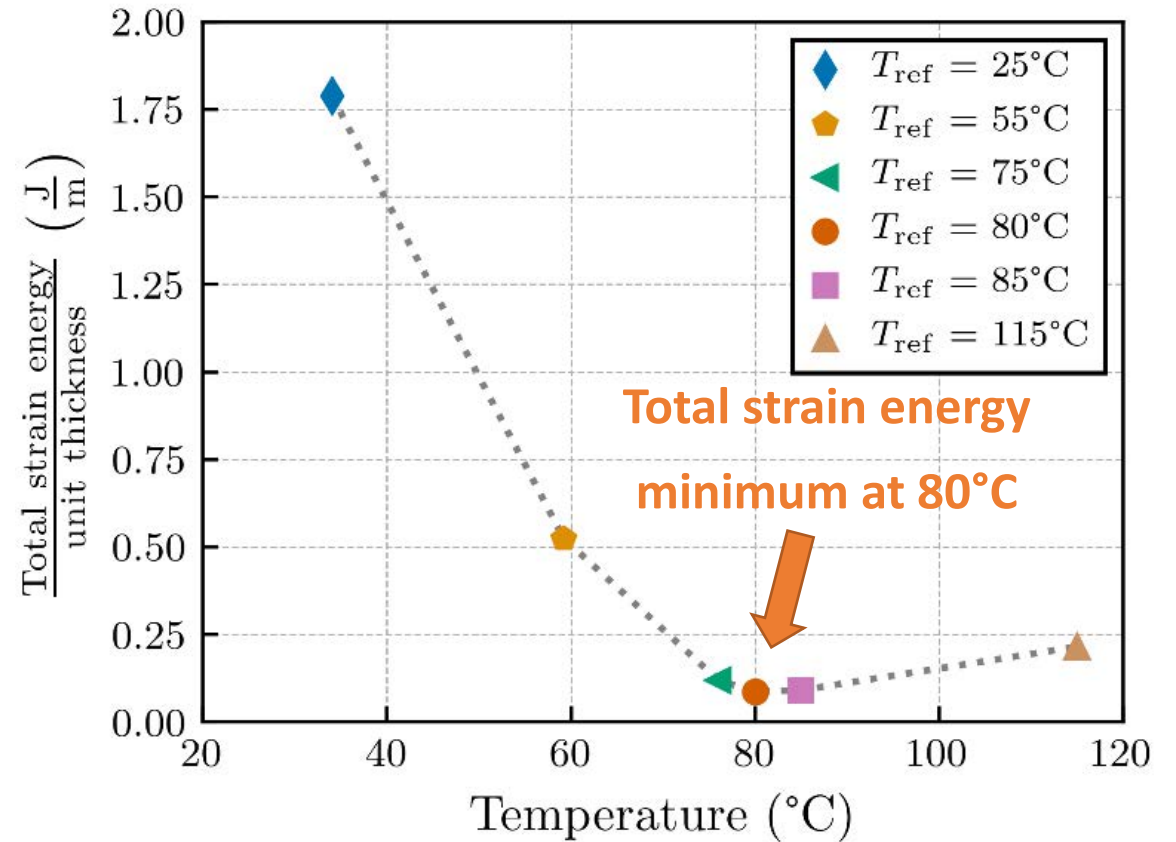
Simulations to determine simulation starting point.

minimum strain energy found to exist at ~80 C

*thermal cycles with different reference temperatures*



*total strain energy minimum*





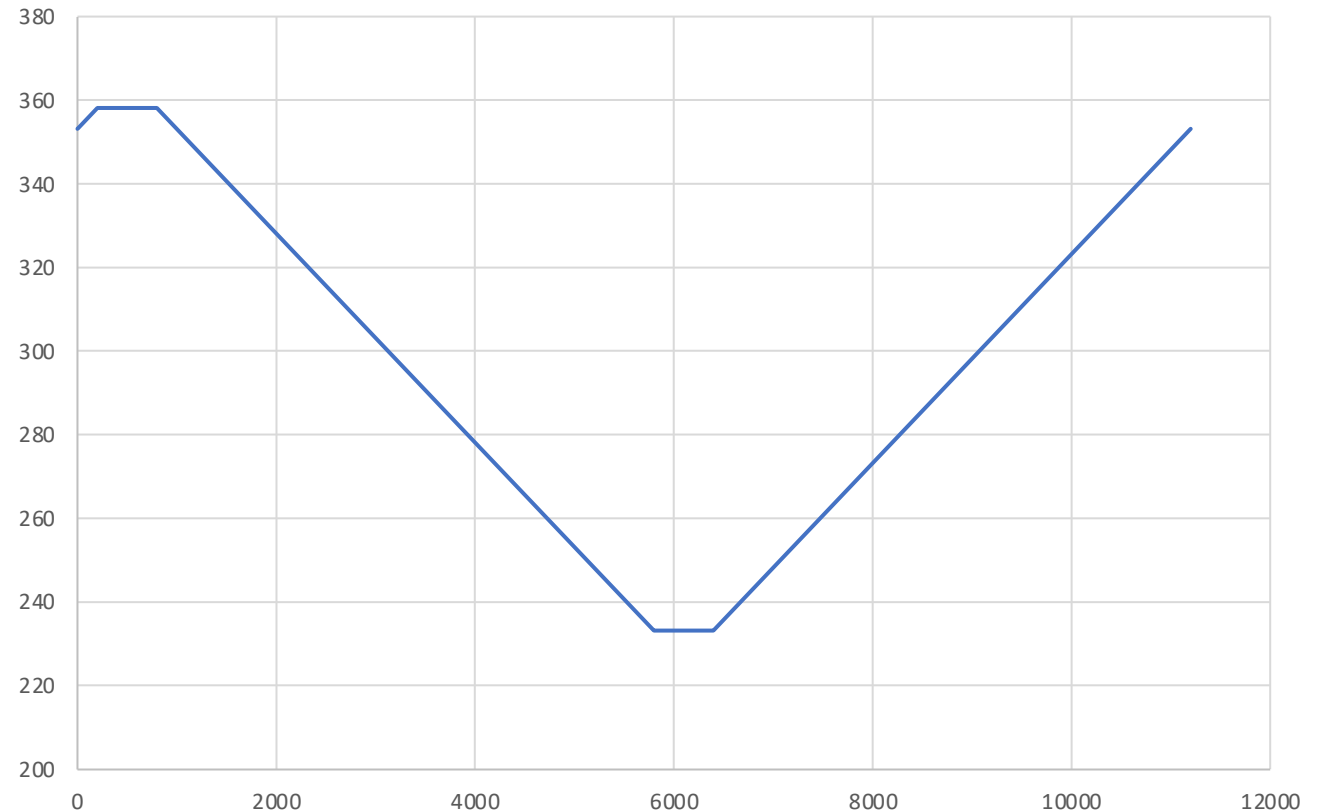
# simulation

A standard accelerated thermal cycle is applied to the 3D full sized module model

The cycle is started at the minimum energy temperature

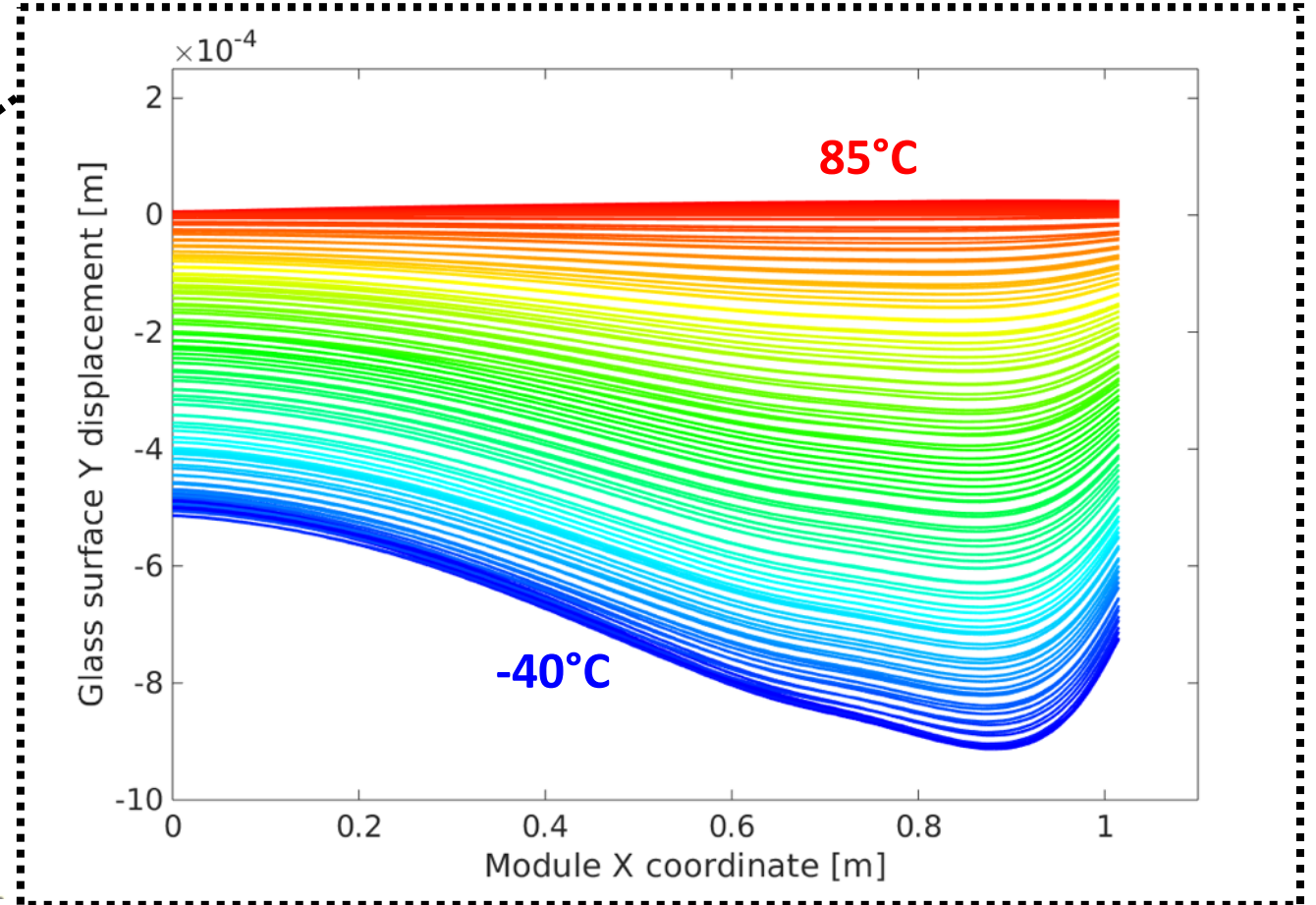
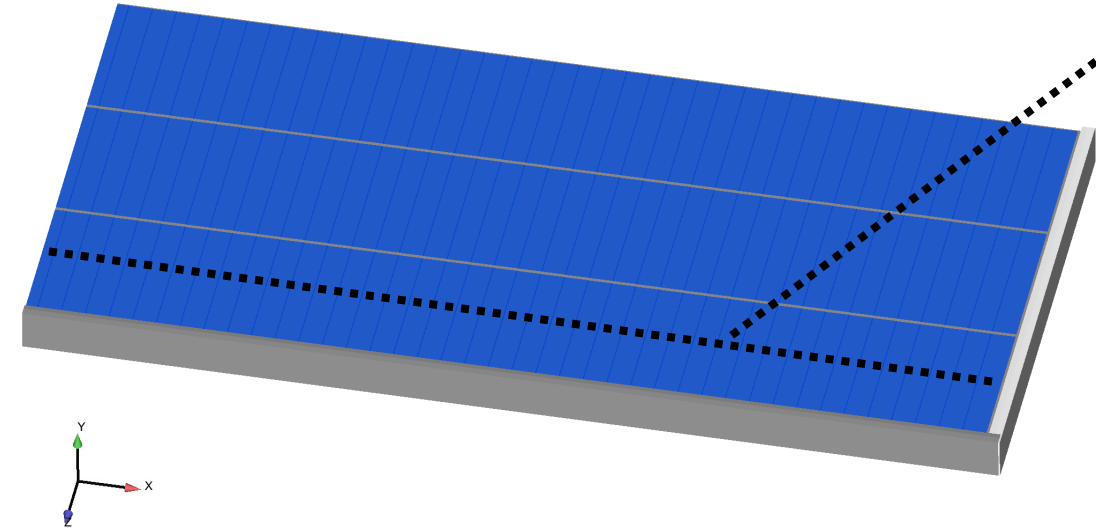
Time (s)	Temp (C)
0	80
200	85
800	85
5800	-40
6400	-40
11200	80

Thermal cycle vs. time (kelvin; seconds)



# 3D simulation results

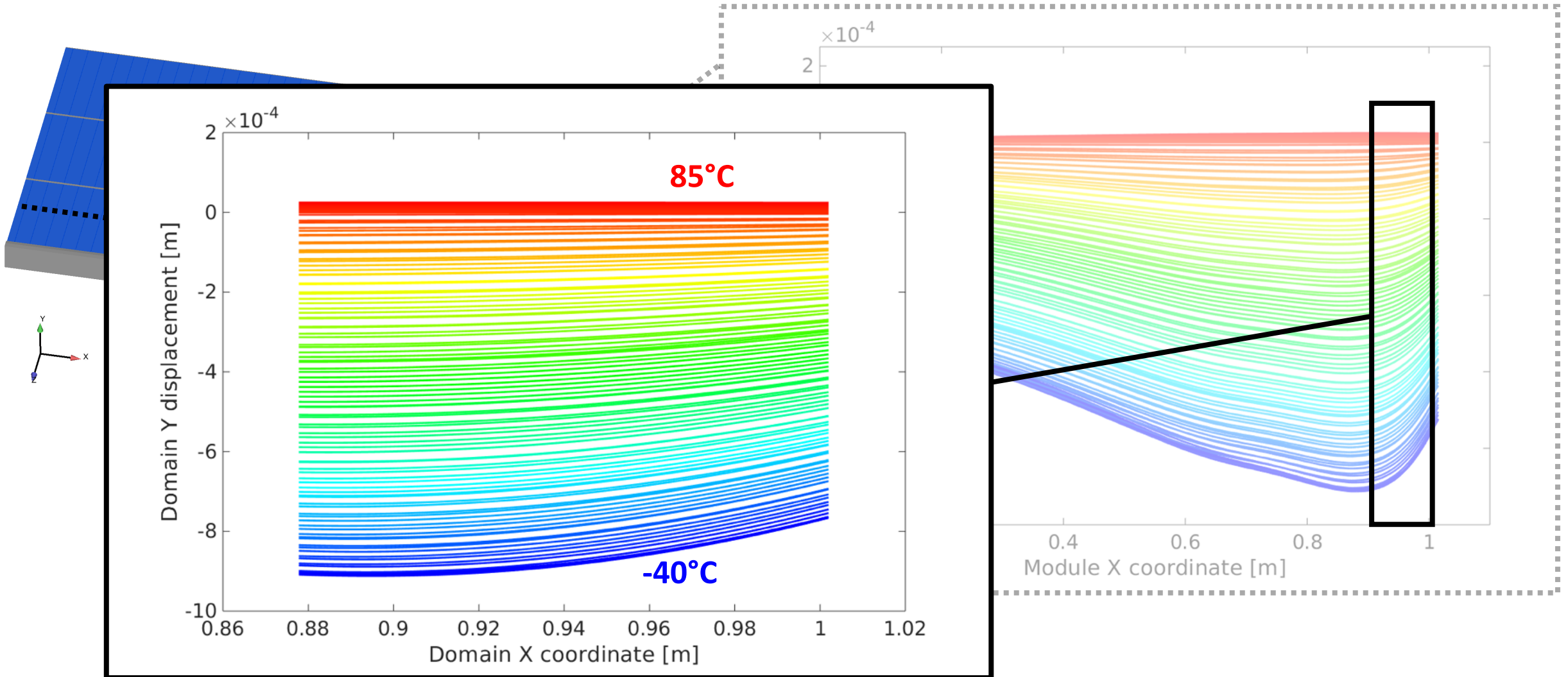
out of plane deflection of outer most string



Full module curvatures during a thermal cycle, over frame row (host for most curved domain)

# 3D simulation results

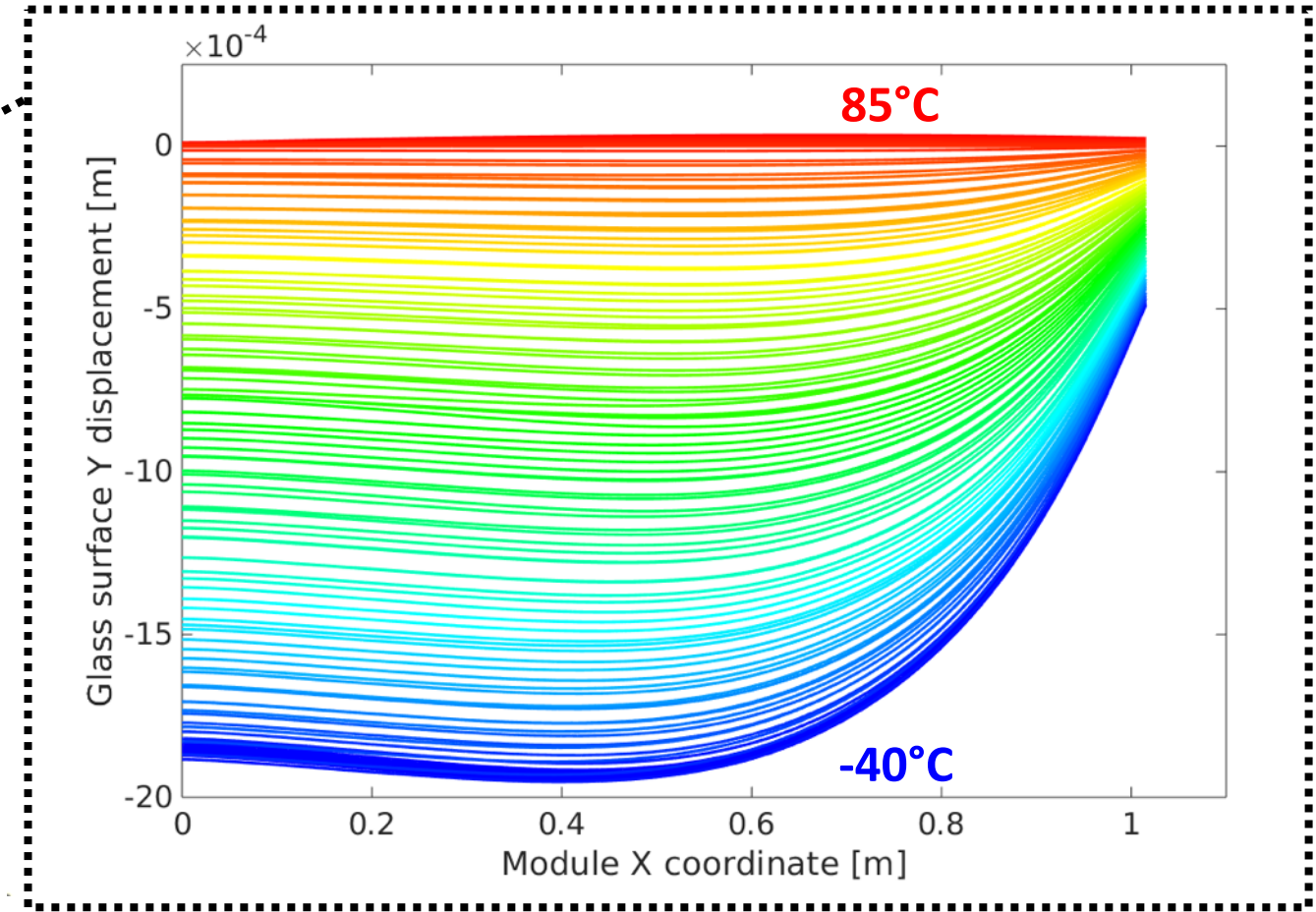
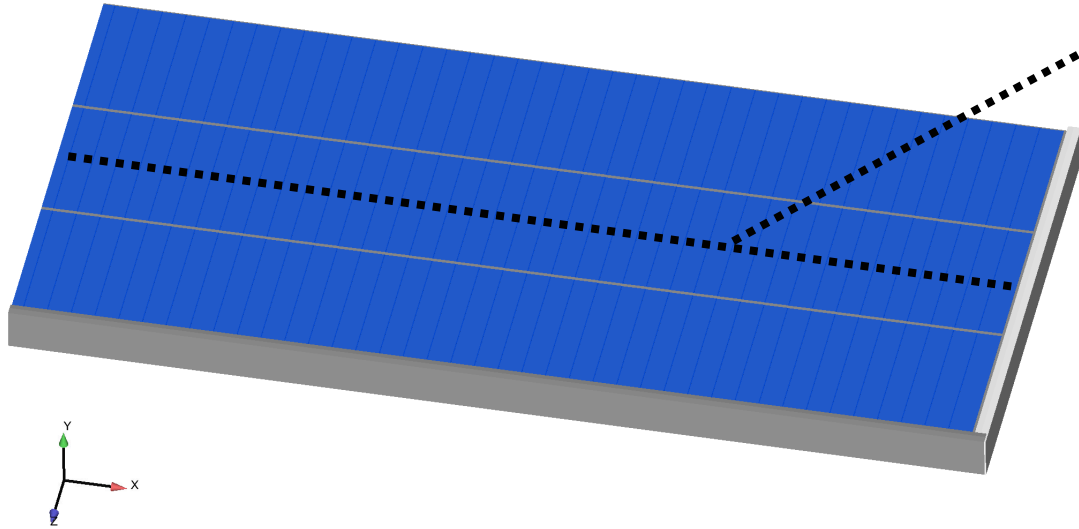
out of plane deflection of outer most string



Most curved 5-cell domain over a thermal cycle

# 3D simulation results

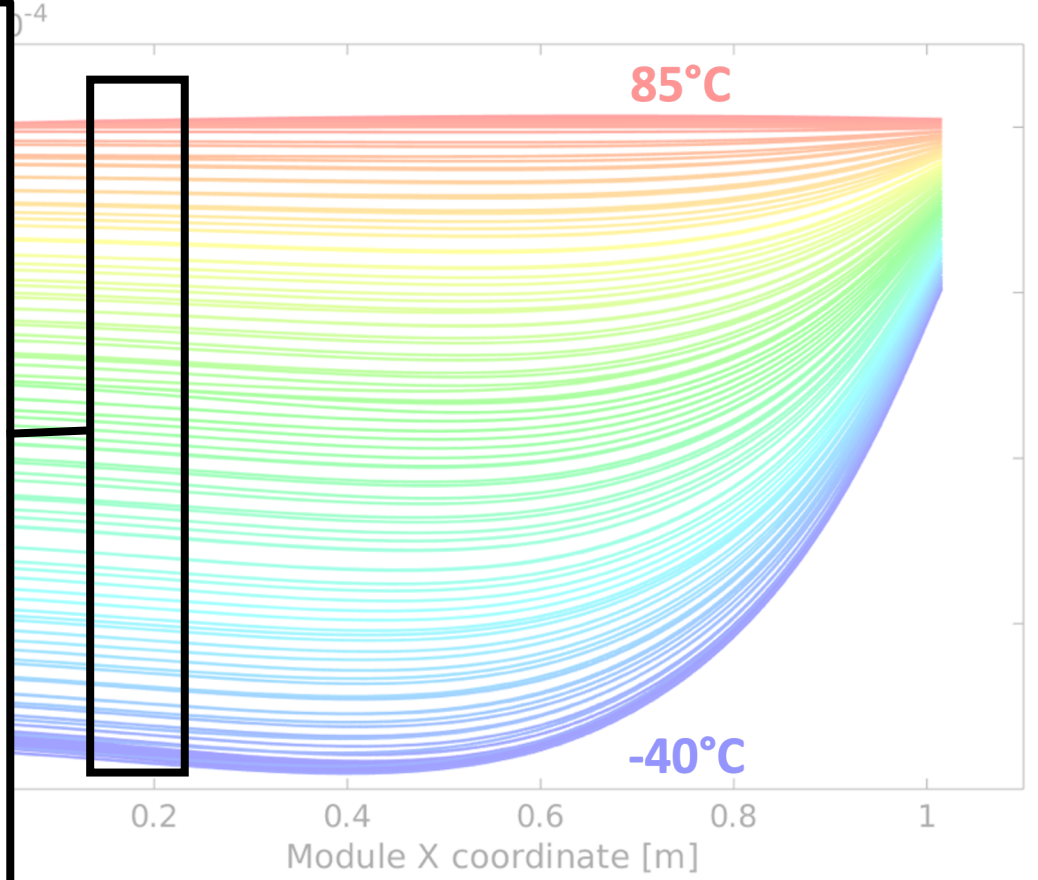
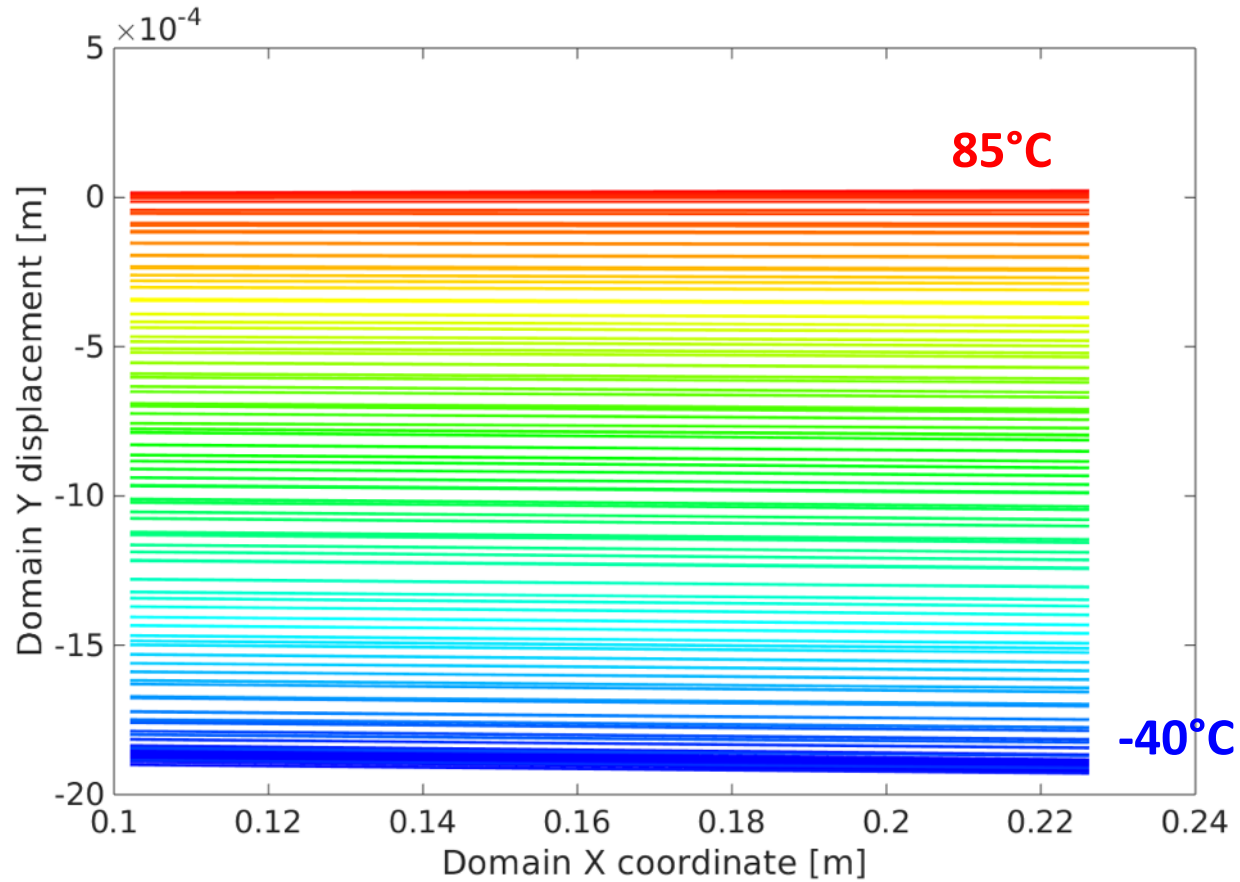
out of plane deflection of adjacent string



Full module curvatures during a thermal cycle, over 2<sup>nd</sup> row (host for flattest domain)

# 3D simulation results

out of plane deflection of adjacent string

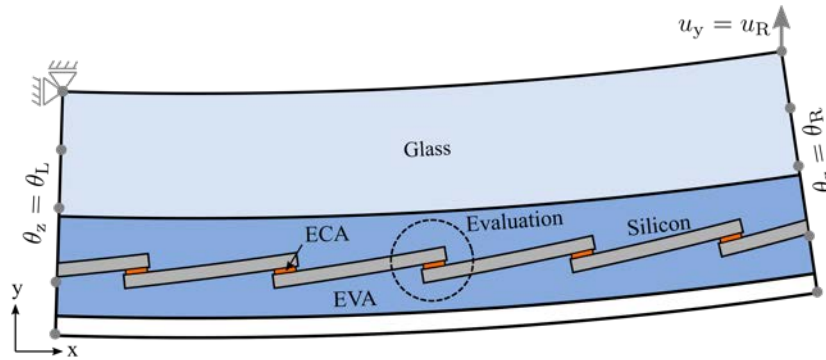


Flattest 5-cell domain over a thermal cycle

# 2D simulations

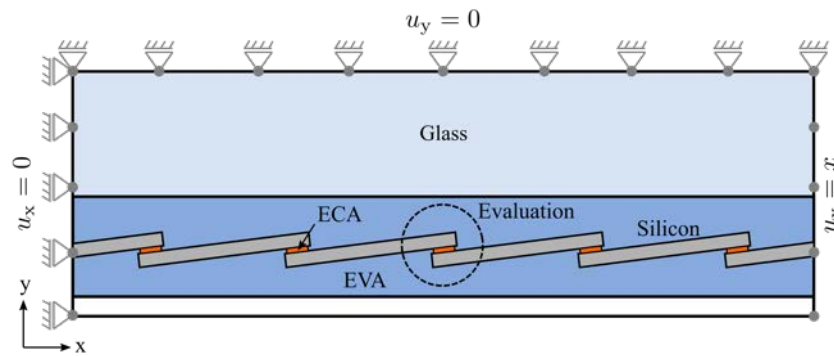
## boundary conditions

### rotation



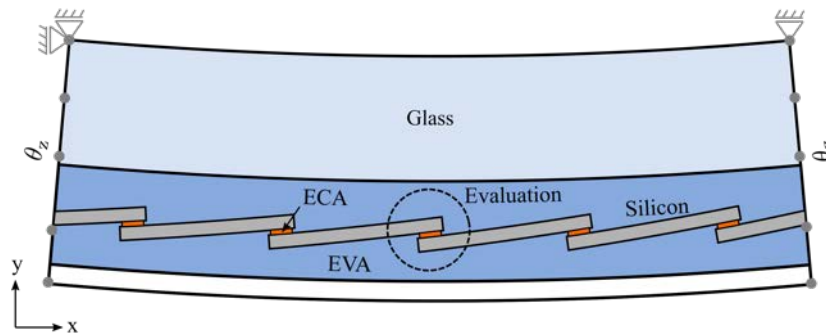
- rigid body movement constrained at top left corner
- left and right surface rotation constrained to 3D full size model output
- top right corner y displacement applied from 3D full size model output

### flat



- left and right surface displacement constrained in x direction
- top surface displacement constrained in y direction

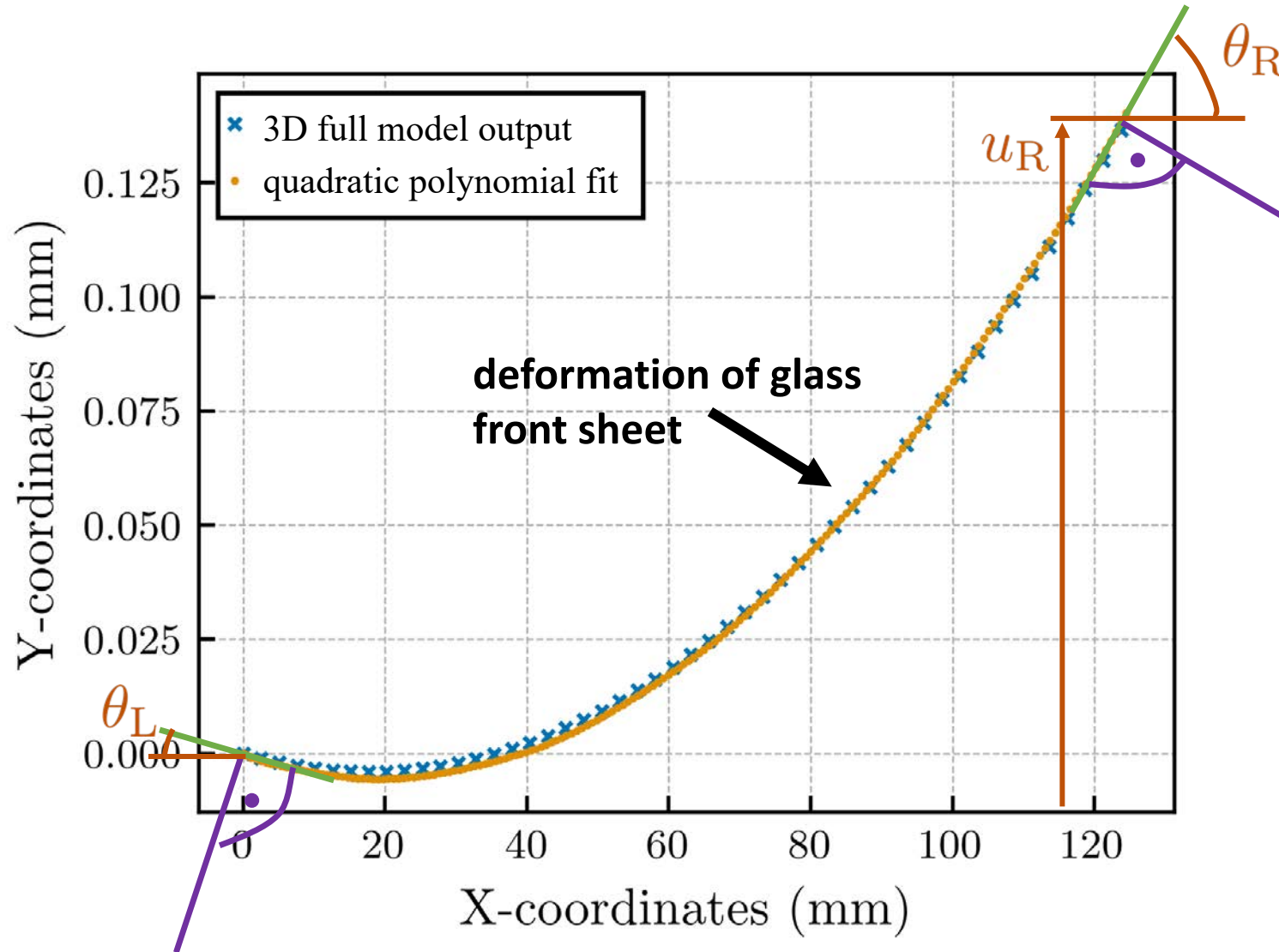
### free



- rigid body movement constrained at top left corner
- y displacement constrained at top right corner to avoid model rotation.

# 2D simulations

## boundary conditions



### Polynomial fit

$$y = C_0 + C_1x + C_2x^2$$

### Derivative

$$y' = C_1 + 2C_2x$$

### Boundary conditions

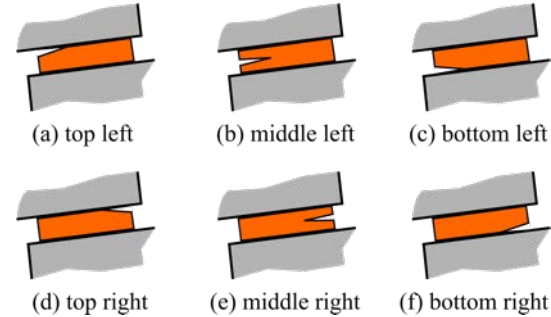
$$\theta = \arctan(y')$$

$$u_R = u_y$$

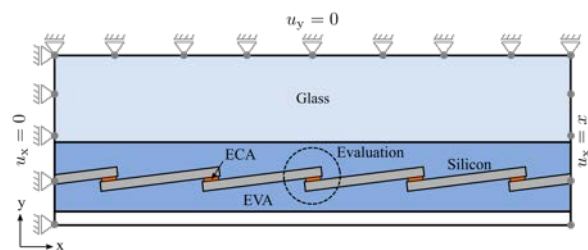
### Submodel edges

assumed to remain straight throughout the simulation

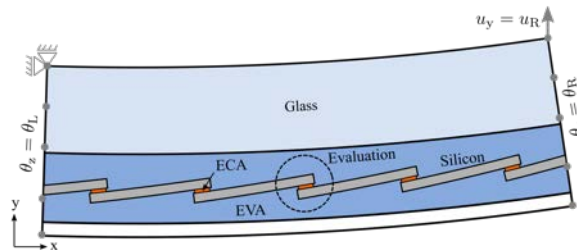
# 2D submodel results mode I



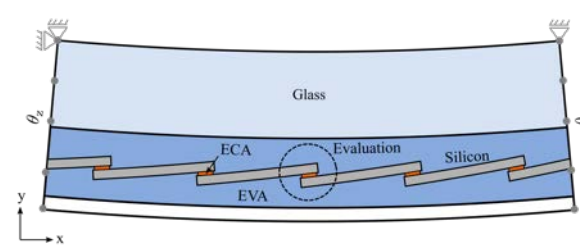
**flat**



**rotation**



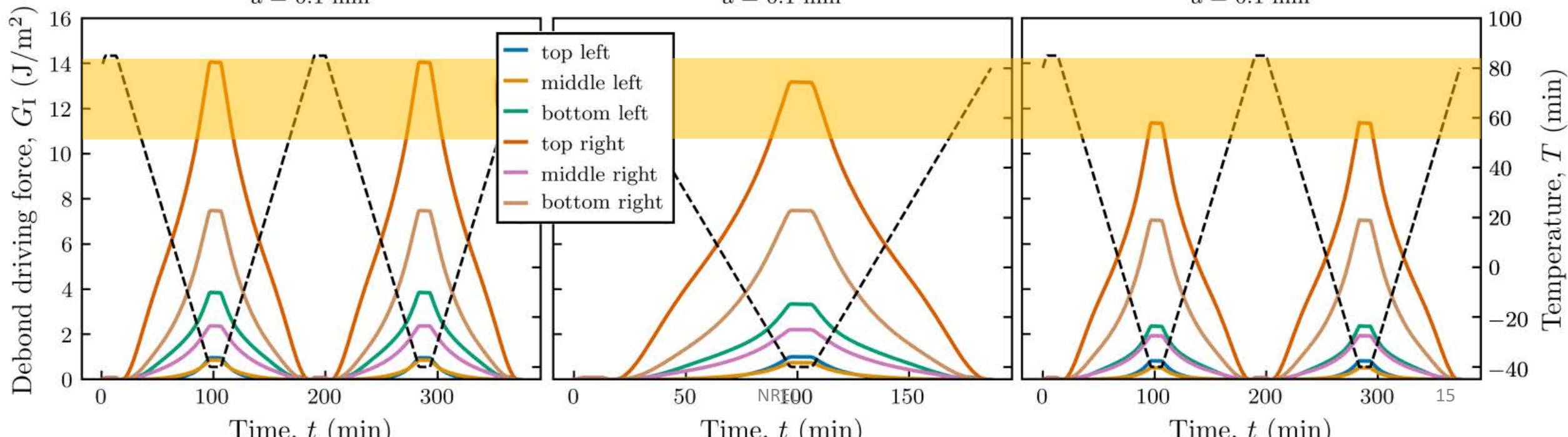
**free**



$a = 0.1 \text{ mm}$

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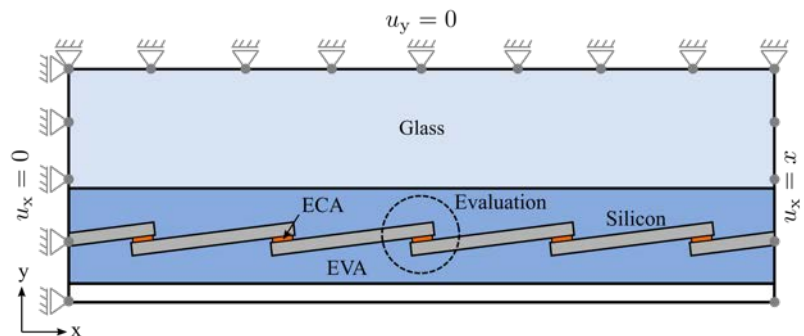
$a = 0.1 \text{ mm}$



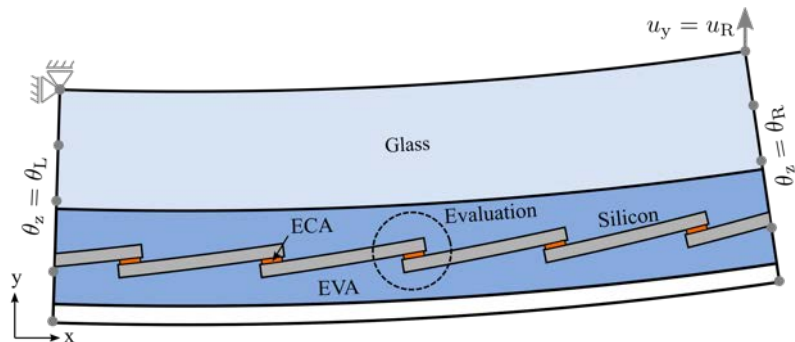


# 2D submodel results mode I

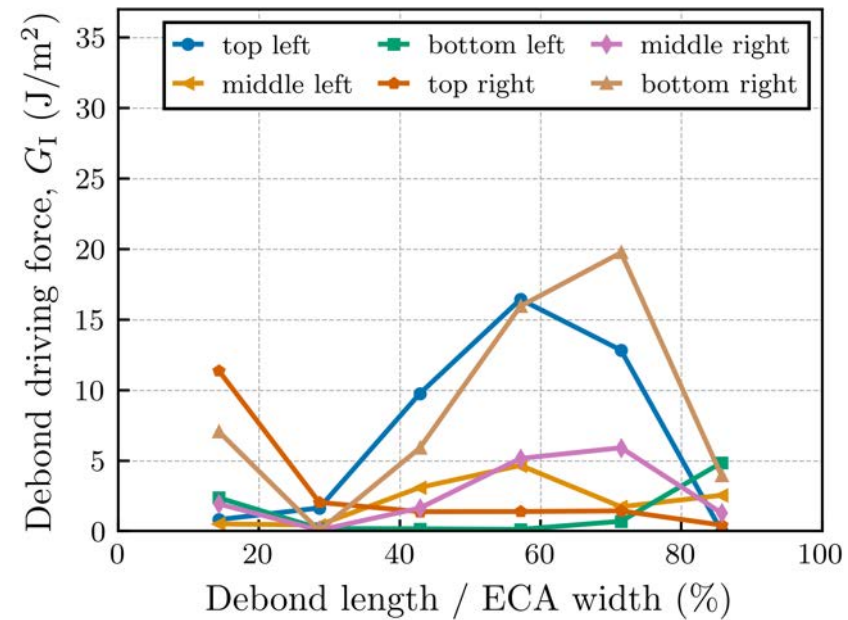
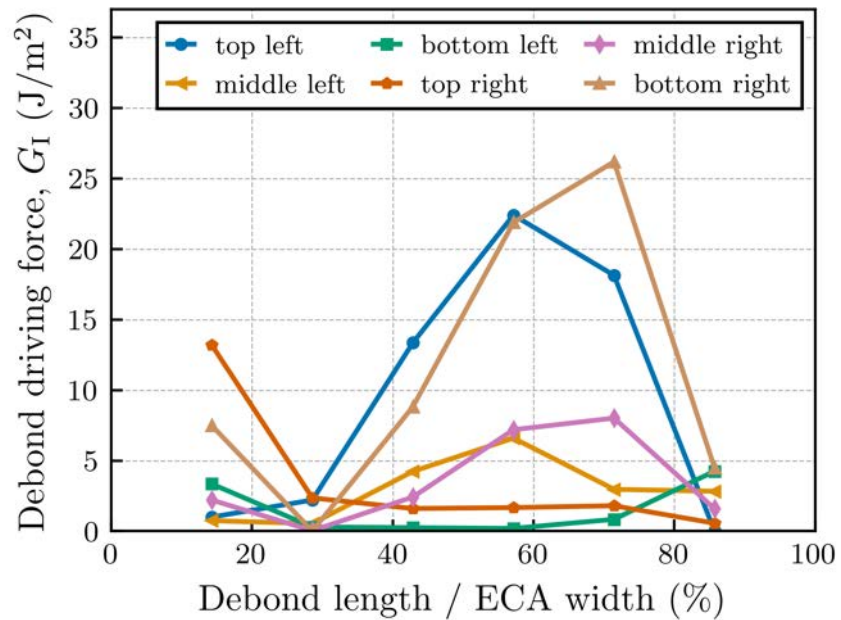
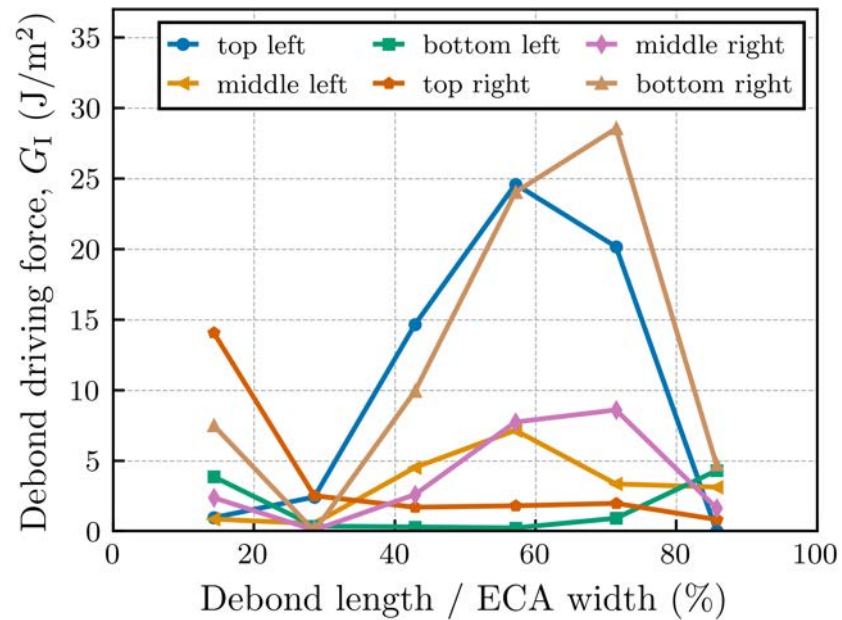
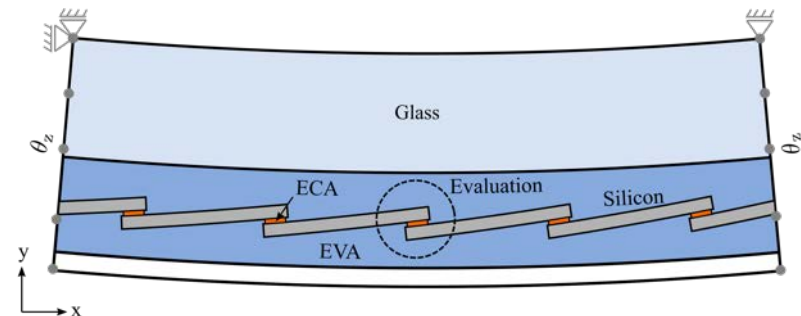
**flat**



**rotation**

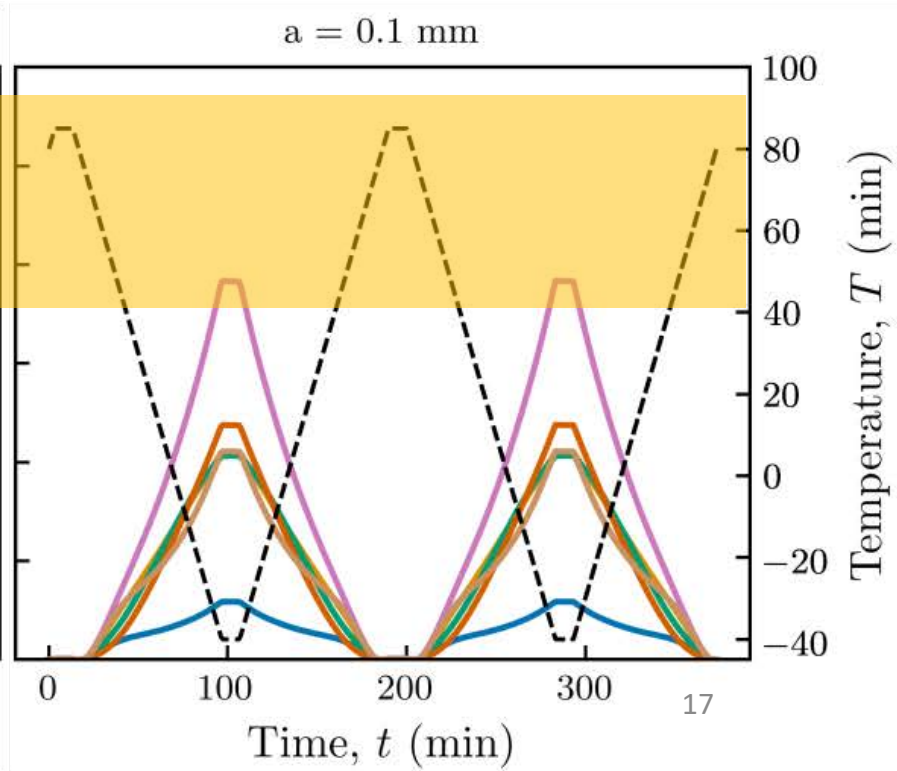
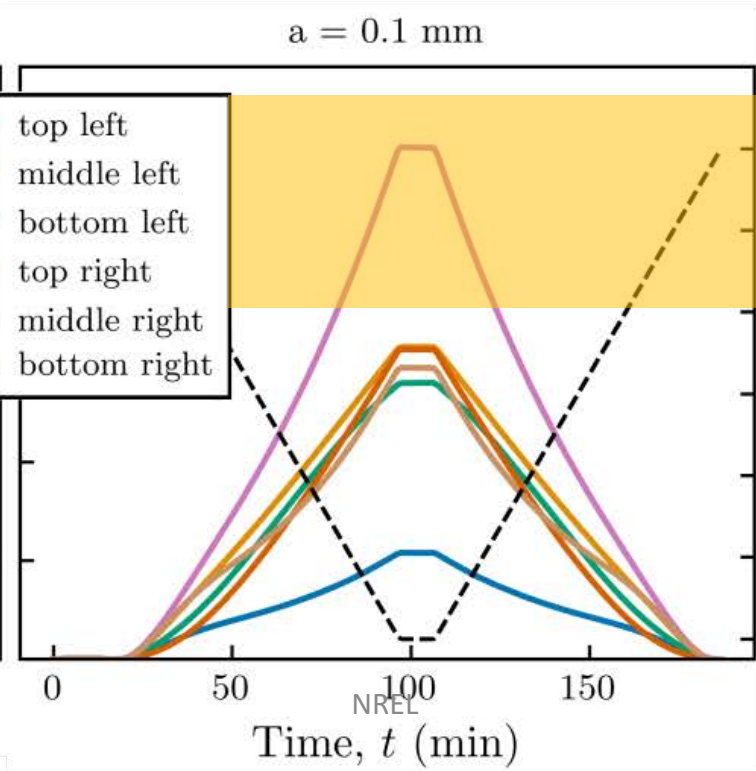
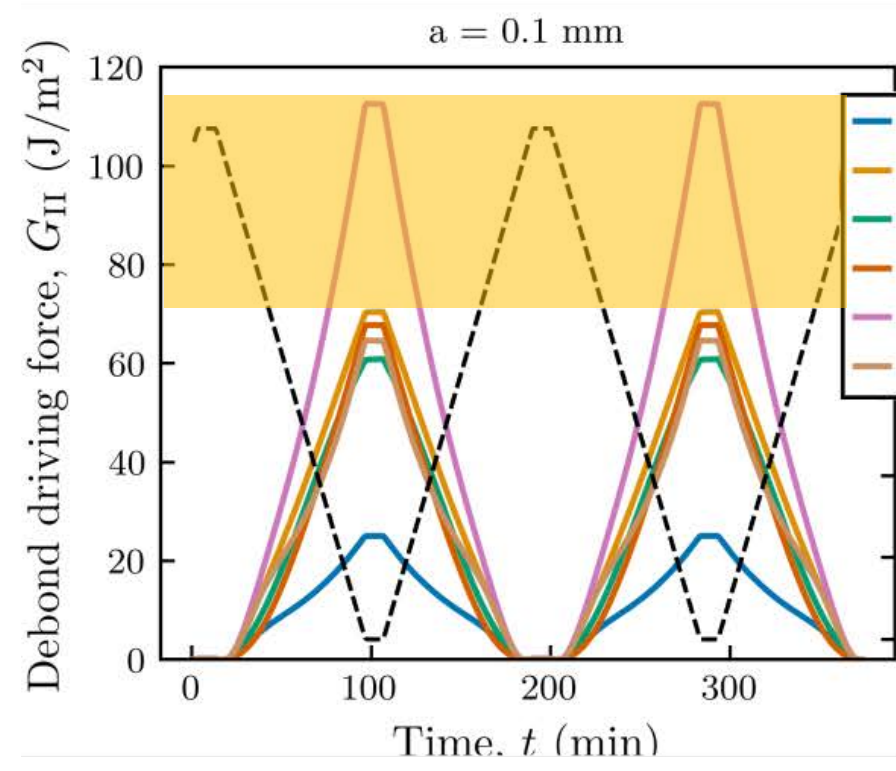
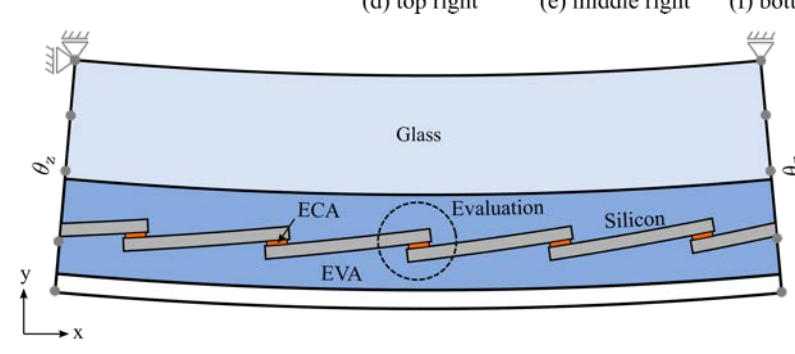
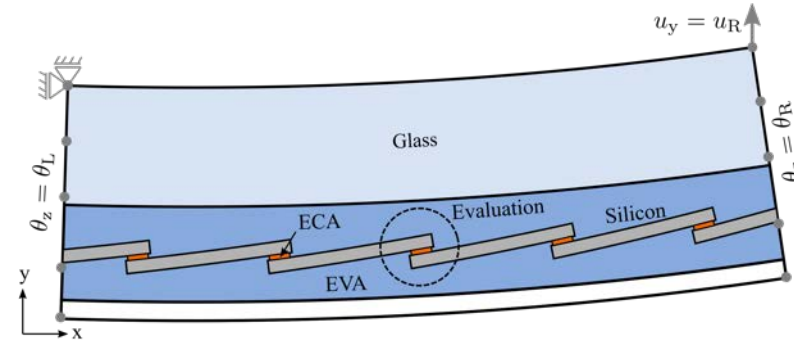
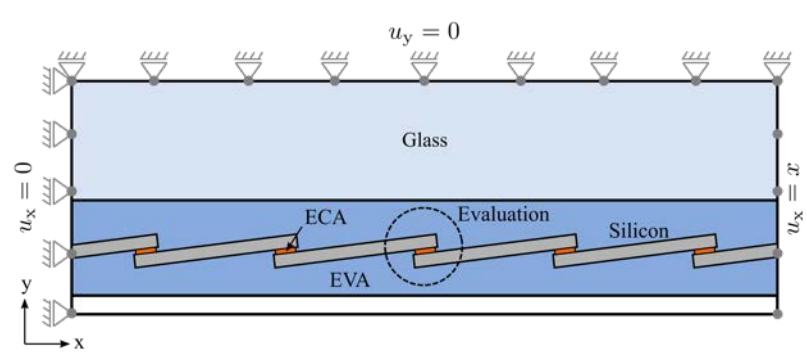
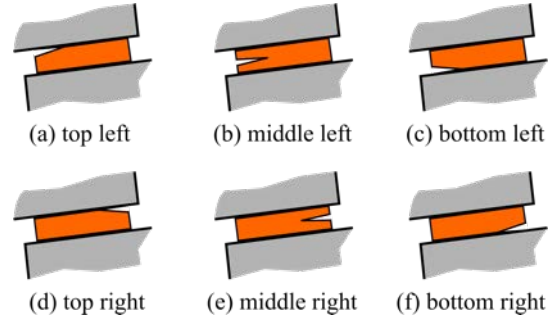


**free**



# 2D submodel results

## mode II

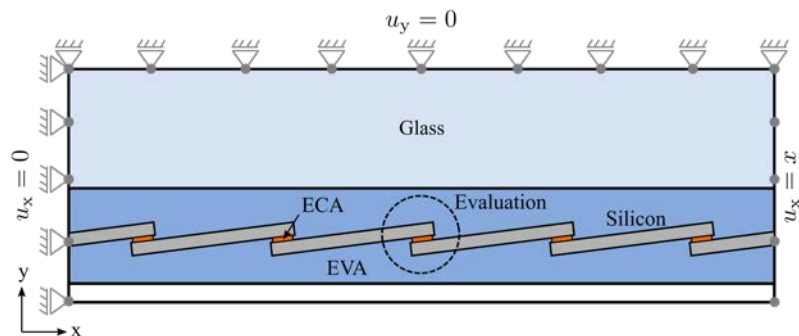


Temperature,  $T$  (min)

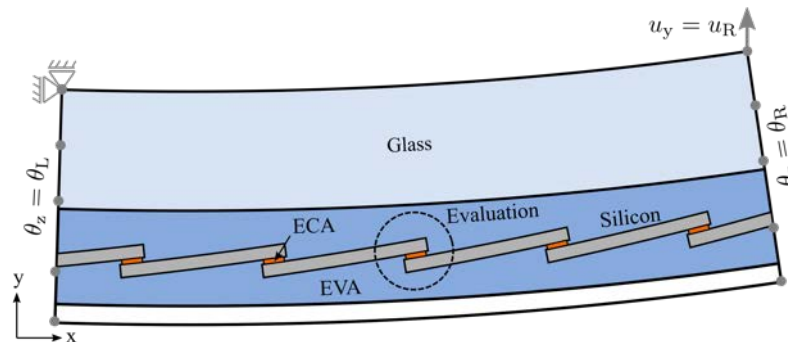
# 2D submodel results

## mode II

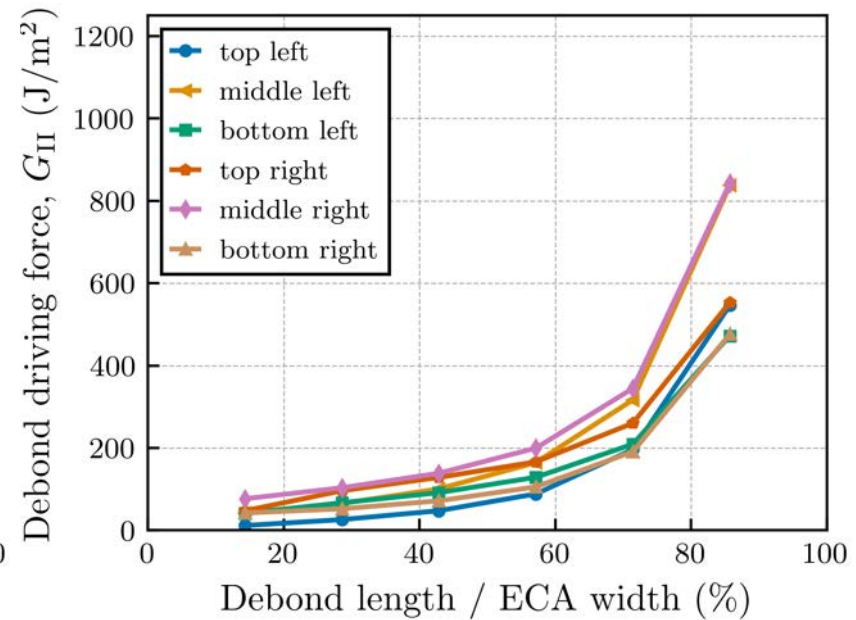
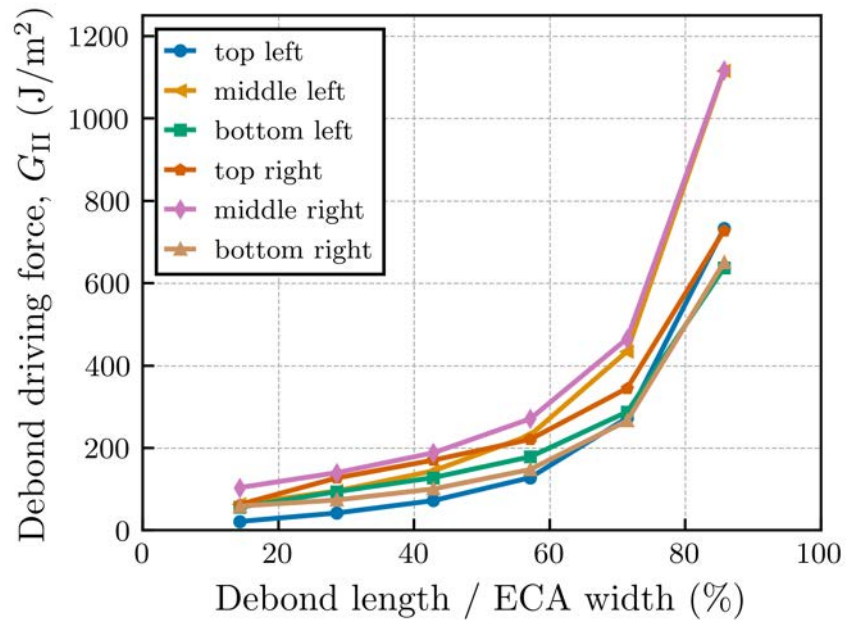
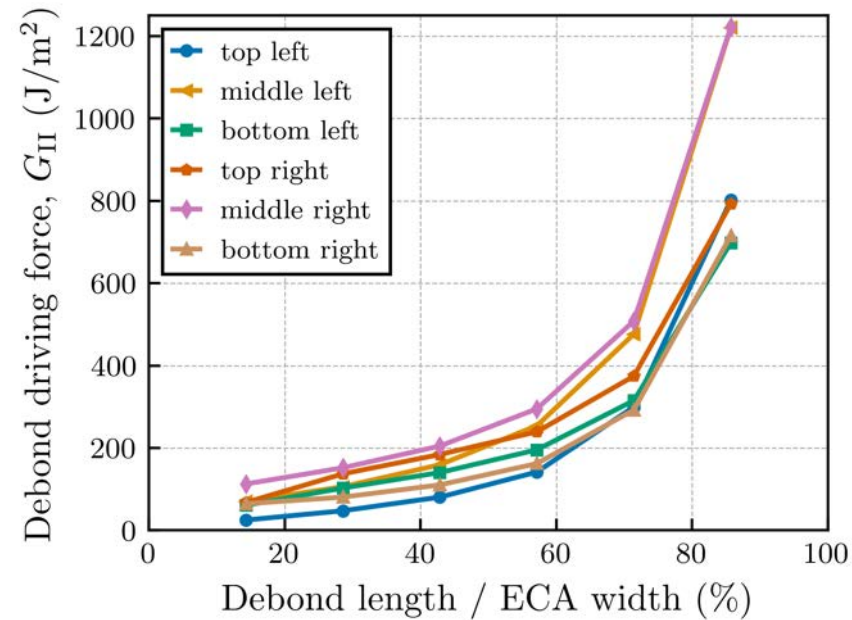
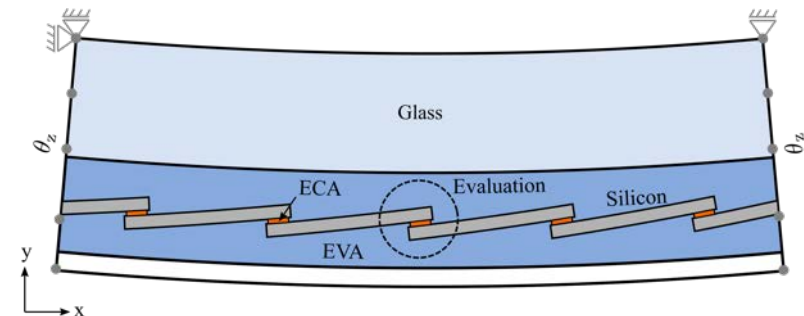
**flat**



**rotation**

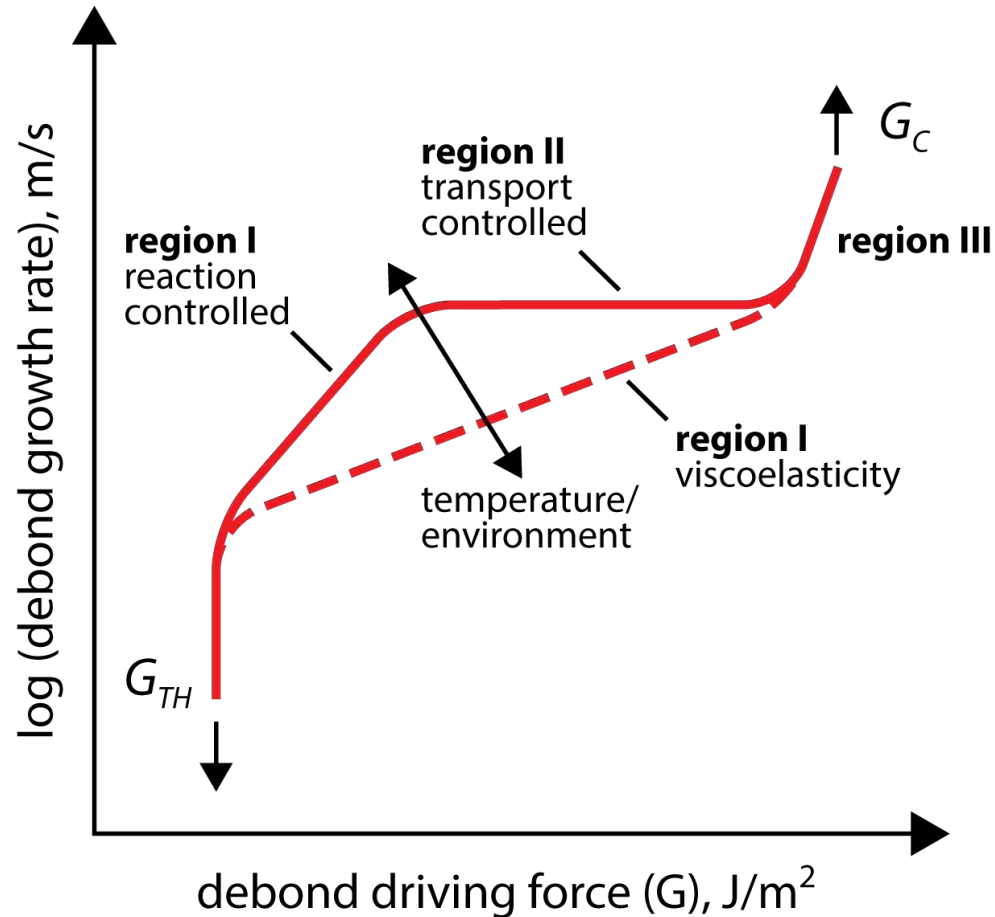


**free**



# Analysis

## fracture criterion



### mode I

$$G_c(-20C) > 500 \text{ J/m}^2$$

$$G_c(45C) > 450 \text{ J/m}^2$$

$$G_{th}(-20C) < 350 \text{ J/m}^2$$

### mode II

$$G_c(-20C) > 800 \text{ J/m}^2$$

$$G_c(45C) > 1000 \text{ J/m}^2$$

$$G_{th}(-20C) < 500 \text{ J/m}^2$$

However, following extensive exposure to moisture:

### mode I

$$G_c(45C) < 100 \text{ J/m}^2$$

$$G_{th}(45C) < 20 \text{ J/m}^2$$

### mode II

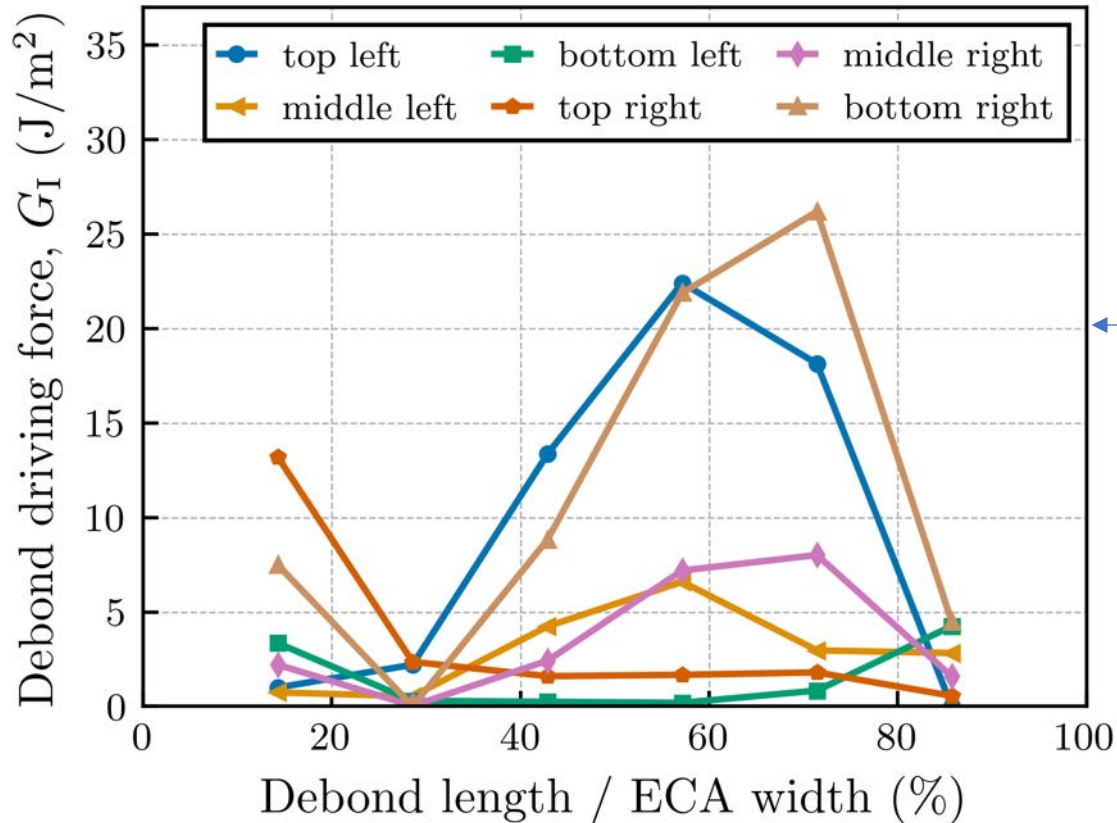
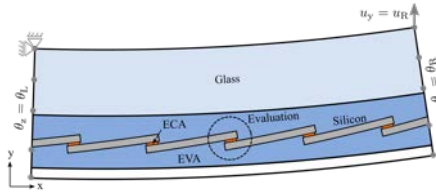
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# Analysis

## fracture criterion

### rotation



$G_{th}(45C) < 20 \text{ J/m}^2$

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moisture degraded

### mode I

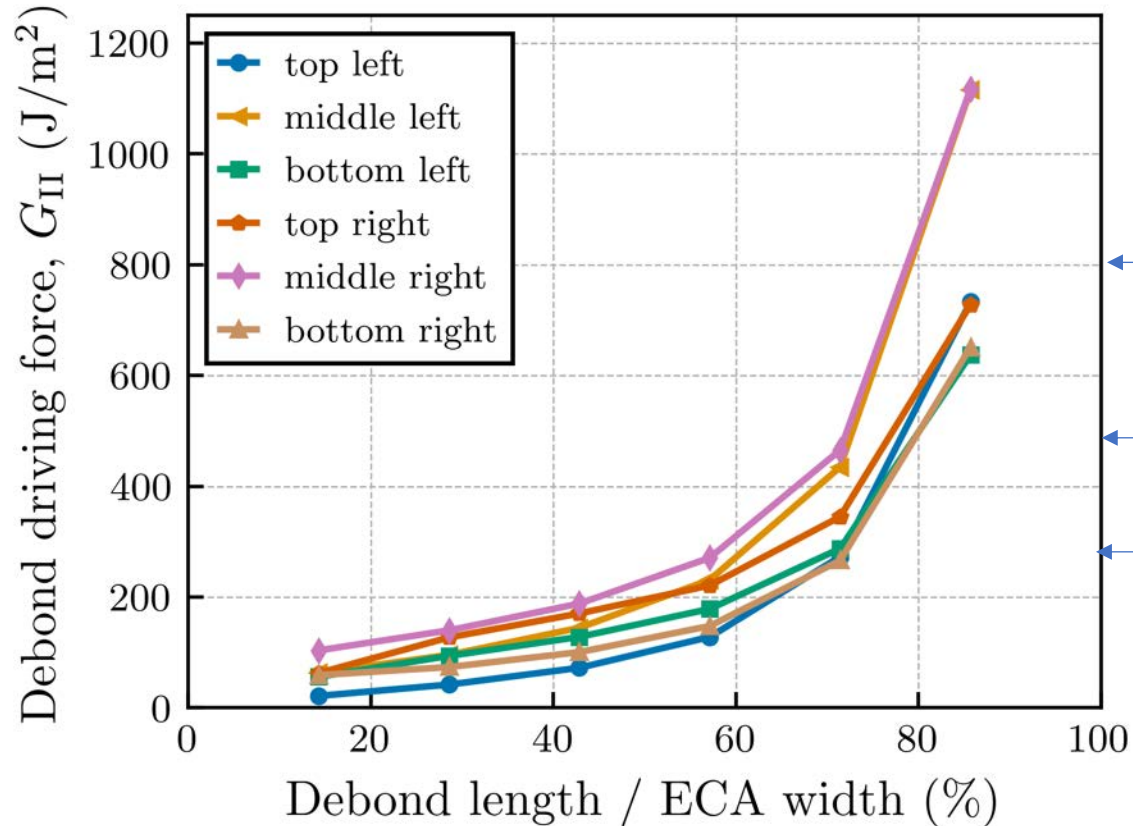
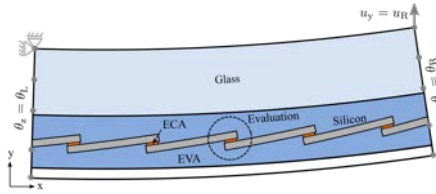
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# Analysis

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$$G_c(45C) > 1000 \text{ J/m}^2$$

$$G_{th}(-20C) < 500 \text{ J/m}^2$$

moisture degraded

### mode II

$$G_c(45C) > 800 \text{ J/m}^2$$

$$G_{th}(45C) < 300 \text{ J/m}^2$$

# conclusions

We've demonstrated a multiscale modeling approach for ECA interconnect degradation

- developed a method to determine the minimum stress temperature
- this needs to be the starting point for any simulation
- likely similar for any glass/backsheet module construction

Demonstrated how the solutions for 2D submodel extrema bound the MSM result

When ECA defects become a large fraction of their width, critical and subcritical failure can be activated

# Thank You

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[www.nrel.gov](http://www.nrel.gov)

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